

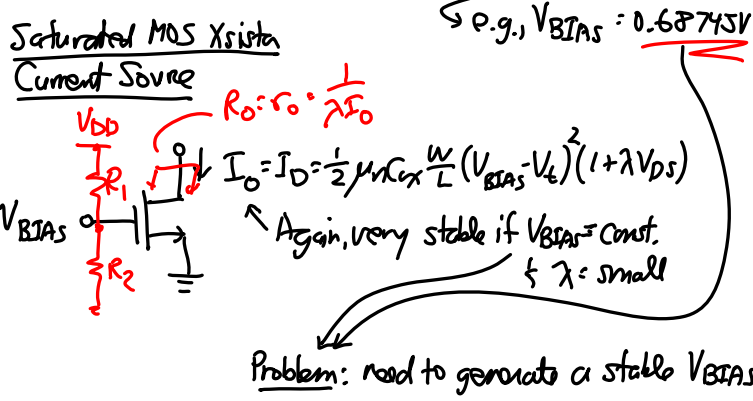
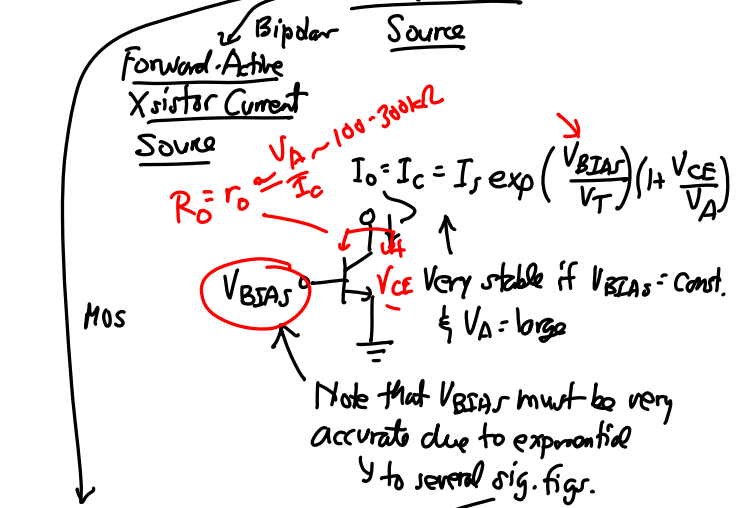
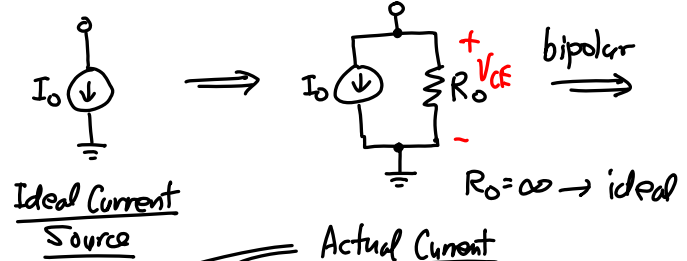
Lecture 9: Current Sources

- Announcements:
 - ↳ HW#4 online
 - ↳ Lab#1 in progress: make sure you have the updated lab version
- Lecture Topics:
 - ↳ Current Source Review
 - ↳ Widlar Current Source
 - ↳ Supply & Temperature Independent Biasing
- -----
- Last Time:
- Finished active load inspection analysis examples
- Now, start a new topic: Current Sources

over

Transistor Current Sources

How can a transistor implement a current source?



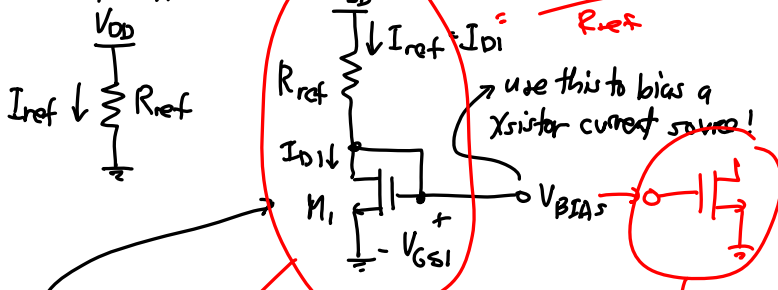
We now focus on methods for generating V_{BSAS} .
But how do we get this degree of precision using a transistor ckt?

Solution: \rightarrow

Replica Biasing (a simple & effective approach)

- ① Generate the desired current.
 - ② Push the current through a χ istor and allow it to reach a stable bias pt.
 - ③ Use this stable bias pt. as V_{BSAS}
- \rightarrow this can be very precise!

One simple approach:



A diode-connected χ istor is always in saturation and will basically bias itself to support the needed current!

$$I_{ref} = I_{D1} = \frac{1}{2} \mu_n C_{ox} \left(\frac{W}{L} \right)_1 (V_{GS1} - V_t)^2 (1 + \lambda V_{DS1})$$

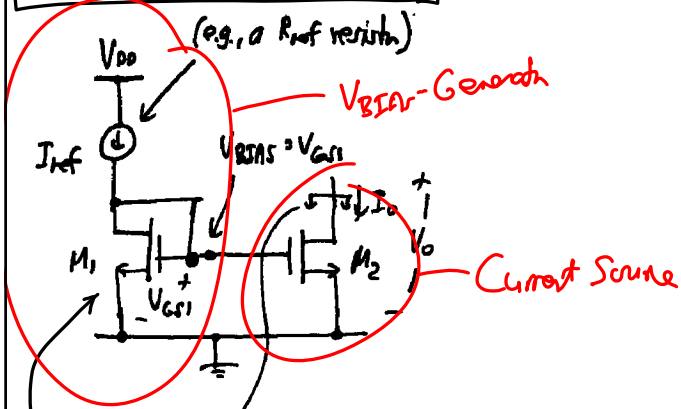
\uparrow
 V_{BSAS}

Current Source

V_{BSAS} -Generator

Now, can distribute this V_{BSAS} to the gates of many MOS transistor current sources!

Ex. Simple MOS Current Source



$$r_o = r_{o1} = \frac{1}{\lambda I_o}$$

In general,

Diode-connected χ istor \rightarrow saturation:
 $I_{D1} = \frac{1}{2} \mu_n C_{ox} \left(\frac{W}{L} \right)_1 (V_{BSAS} - V_t)^2 (1 + \lambda V_{DS1})$
 $I_{D2} = \frac{1}{2} \mu_n C_{ox} \left(\frac{W}{L} \right)_2 (V_{BSAS} - V_t)^2 (1 + \lambda V_{DS2})$

$V_{DS1} \neq V_{DS2}$, but if λ is small, then little difference in I_{D1} & I_{D2}

① Case: matched M_1 & $M_2 \Rightarrow I_o = I_{ref}$

② Case: M_1 & M_2 scaled wr to each other

$$\Rightarrow I_o = I_{ref} \frac{(W/L)_2}{(W/L)_1}$$

\Rightarrow use $L_1 = L_2$ for better accuracy, then:

$$\frac{I_o}{I_{ref}} = \frac{W_2}{W_1}$$

Note: for better accuracy, should use multiple copies of one device when scaling currents \rightarrow reduces edge effects!

Ex: Layout for a Doubling Current Source

I_{ref} , V_{BSAs} , $I_{O} = 2 I_{ref}$, $(\frac{W}{L})_2 = 2(\frac{W}{L})_1$, $(\frac{W}{L})_2 \neq 2(\frac{W}{L})_1$

A single V_{BSAs} generator can now serve numerous current sources:

V_{DD} , I_{ref} , V_{BSAs} , $2 I_{ref}$, I_{ref} , M_1 , M_2 , M_3 , $2(W/L)_1$, $(W/L)_1$

How about bipolar?

Simple Bipolar Current Source

V_{CC} , I_{ref} , R_{ref} , I_{B1} , I_{B2} , $I_{O} = I_{C2}$, KCL here to get $I_{C2} = f(I_{ref})$, Q_1 , Q_2 , V_{BE1} , V_{BE2}

Assume Q_1 & Q_2 are matched. $V_{BE1} = V_{BE2} \rightarrow I_{C1} = I_{C2} = I_O$ (neglecting V_A 's) i.e., $V_A = \infty$

$I_{ref} = I_{C1} + I_{B1} + I_{B2} = I_{C1}(1 + \frac{2}{\beta})$

$\therefore I_{C1} = I_{C2} = I_O = \frac{I_{ref}}{1 + \frac{2}{\beta}} \rightarrow I_O \approx I_{ref}$

and $I_{ref} = \frac{V_{CC} - V_{BE(on)}}{R_{ref}}$ $R_{O1} = r_{O2}$ can say error $\sim \frac{2}{\beta}$

Again, a single V_{BSAs} generator can serve many current sources throughout the IC chip:

V_{CC} , I_{ref} , R_{ref} , I_{C1} , I_{B1} , V_{BSAs} , I_{B2} , I_{O} , Q_1 , Q_2 , Q_3 , Q_n , I_{Bn}

$I_{ref} = I_{C1} + I_{B1} + I_{B2} + I_{B3} + \dots + I_{Bn}$

[Identical X 's exist] $\Rightarrow I_{ref} = I_{C1}(1 + \frac{n}{\beta})$

$\Rightarrow I_O = I_{C1} = \frac{I_{ref}}{(1 + \frac{n}{\beta})}$

Problem: error $\sim \frac{n}{\beta}$ increases as n (I_O divider from I_{ref} , and % deviation depends on n .)

How can one reduce the error?

$$V_{BE1} = V_{BE2} + V_{R_2} = V_{BE2} + \frac{1}{\alpha} I_{C2} R_2 \approx V_{BE2} + I_{C2} R_2$$

$$I_{C2} R_2 = V_{BE1} - V_{BE2} = V_T \ln \frac{I_{C1}}{I_{C1'}} - V_T \ln \frac{I_{C2}}{I_{C2'}}$$

$$I_{C2} R_2 = V_T \ln \frac{I_{C1}}{I_{C2}} \quad (\text{Assuming } \alpha_1 \approx \alpha_2 \text{ are matched.})$$

$$I_{O} R_2 = V_T \ln \frac{I_{ref}}{I_O}$$

Rule of Thumb: $V_{R_2} = I_{C2} R_2$

V_{R_2}	$I_{C2} = I_O$
18mV	$\frac{1}{2} I_{ref}$
42mV	$\frac{1}{5} I_{ref}$
60mV	$\frac{1}{10} I_{ref}$
120mV	$\frac{1}{100} I_{ref}$

→ Just example again

Ex: scale by 100x using Widlar source

$$V_{BE1} - V_{BE2} = 120mV \rightarrow R_2 = \frac{120mV}{5\mu A} = 24k\Omega$$

$$I_{ref} = 500\mu A \rightarrow R_{ref} = \frac{30V}{500\mu A} = 60k\Omega$$

More reasonable than 600kΩ before.

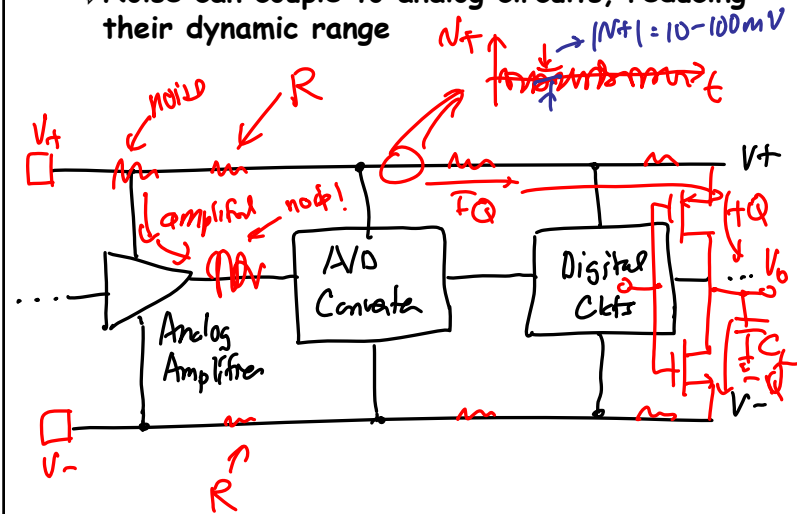
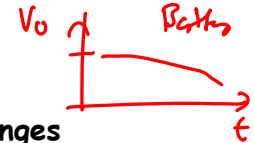
If want smaller, scale by 100x instead.

Another advantage of the Widlar: larger R_O ∴ a more ideal current source:

$$R_O = r_{o2} (1 + g_{m2} R_2)$$

Supply & Temperature Independent Biasing

- Why is it necessary?
- For battery-operated systems, battery voltages vary over time
 - ↪ Amplifier gains change
 - ↪ Power consumption changes
 - ↪ Frequency of oscillators changes
 - ↪ In summary: long-term stability degrades
 - ↪ Large uncertainty in biasing translates to overdesign that wastes power
- Same issues as above when temperature varies with time
 - ↪ $I_C = I_{exp} \left(\frac{V_{BE}}{V_T} \right)$
- Short-term supply variations
 - ↪ In mixed signal circuits, i.e., both analog and digital together, digital switching generates noise on the supply lines
 - ↪ Noise can couple to analog circuits, reducing their dynamic range

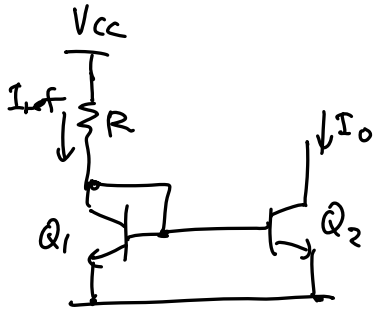


Define: Sensitivity of Y to X

$$S_X^Y = \frac{\frac{\Delta Y}{Y}}{\frac{\Delta X}{X}} = \frac{X}{Y} \frac{\Delta Y}{\Delta X} = \frac{X}{Y} \frac{\partial Y}{\partial X}$$

For supply dependence, we want $S_{V_{CC}}^{I_0} = 0$.

Simple Current Source



Neglecting base currents:

$$I_0 = I_{ref} \cdot \frac{V_{CC} - V_{BE(Q2)}}{R}$$

$$I_0 \approx \frac{V_{CC}}{R} \quad [V_{CC} \gg V_{BE(Q2)}]$$

Thus:

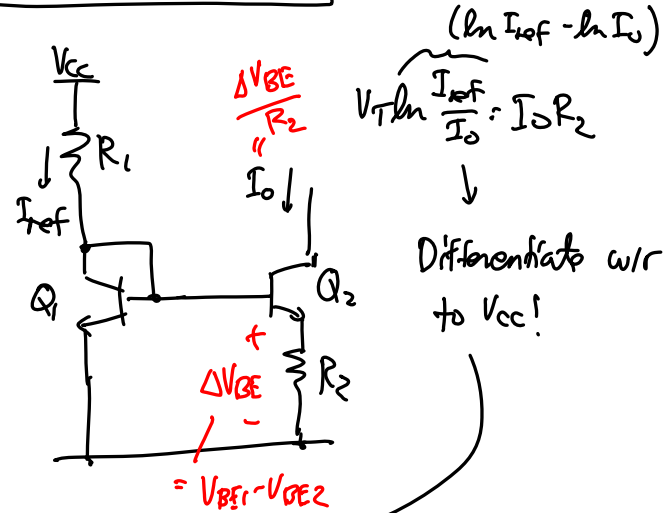
$$S_R^{I_0} = \frac{R}{I_0} \frac{\partial I_0}{\partial R} = \frac{R^2}{V_{CC}} \left(-\frac{1}{R^2}\right) \Rightarrow S_R^{I_0} = -1$$

$$S_{V_{CC}}^{I_0} = \frac{V_{CC}}{I_0} \frac{\partial I_0}{\partial V_{CC}} = R \left(\frac{1}{R}\right) \Rightarrow S_{V_{CC}}^{I_0} = 1$$

∴ a 10% change in V_{CC} leads to 10% change in I_0 !

terrible!

Widlar Current Source (Any better?)



Differentiate w/r to V_{CC} !

$$V_T \left(\frac{1}{I_{ref}} \frac{\partial I_{ref}}{\partial V_{CC}} - \frac{1}{I_0} \frac{\partial I_0}{\partial V_{CC}} \right) = R_2 \frac{\partial I_0}{\partial V_{CC}}$$

↓ math

$$\frac{\partial I_0}{\partial V_{CC}} = \frac{V_T}{I_{ref}} \frac{\partial I_{ref}}{\partial V_{CC}} \left(R_2 + \frac{V_T}{I_0} \right)$$

$$\therefore S_{V_{CC}}^{I_0} = \frac{V_{CC}}{I_0} \frac{\partial I_0}{\partial V_{CC}} = \frac{V_T \left(\frac{V_{CC}}{I_{ref}} \frac{\partial I_{ref}}{\partial V_{CC}} \right)}{I_0 R_2 + V_T}$$

$S_{V_{CC}}^{I_{ref}} = 1$

$$\Rightarrow S_{V_{CC}}^{I_0} \approx \left(\frac{1}{1 + \frac{I_0 R_2}{V_T}} \right) S_{V_{CC}}^{I_{ref}}$$

$$\text{Since } I_{ref} = \frac{V_{CC} - V_{BE(on)}}{R_1} \approx \frac{V_{CC}}{R_1} \Rightarrow S_{V_{CC}}^{I_{ref}} = 1$$

$$\therefore S_{V_{CC}}^{I_0} = \frac{1}{1 + \frac{I_0 R_2}{V_T}}$$

For $I_{ref} = 1\text{mA}$, $I_0 = 10\mu\text{A}$, $R_2 = 11.91\text{k}\Omega$, then

10% Δ in $V_{CC} \rightarrow 1.37\%$ Δ in I_0

(better than the simple current source!)

How can we do better?

\rightarrow Use another voltage reference:



- ✓ ① $V_{BE} \rightarrow$ base emitter junction voltage
- ② $V_Z \rightarrow$ Zener diode
- ③ $V_t \rightarrow$ threshold voltage (MOS)
- ✓ ④ $V_T = \frac{kT}{q} \rightarrow$ thermal voltage
- ✓ ⑤ $E_g \rightarrow$ bandgap